

_	Application No.	Applicant(s)
	10/040,915	TEIG ET AL.
	Examiner	Art Unit
	A. M. Thompson	2825

SEARCHED					
Class	Subclass	Date	Examiner		
716	12	10/1/2004	АМТ		
716	16	10/1/2004	AMT		
716	15	10/1/2004	AMT		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	-	*		
	L.			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
IEEE; USPAT; USPGPUB; DERWENT	10/1/2004	АМТ		
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